

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:
Crawford, et. al.
Serial No.:
Filed: *Herewith* 11/21/03
**Title: System and Method for Process
Driven Quality Measures**

**: Group Art Unit:
Intellectual Property Law Department
International Business
Machines Corporation
Software Group IP Law -- T81/503
3039 Cornwallis Road
Research Triangle Park, NC 27709**

INFORMATION DISCLOSURE STATEMENT

The Assistant Commissioner of Patents
Washington, D.C. 20231

Sir:

Applicants submit herewith patents, publications or other information of which they are aware, which they believe may be material to the examination of this application and in respect of which there may be a duty to disclose in accordance with 37 CFR § 1.56.

While this Information Disclosure Statement may be "material" pursuant to 37 CFR § 1.56, it is not intended to constitute an admission that any patent, publication or other information referred to herein is "prior art" for this invention unless specifically designated as such.

In accordance with 37 CFR § 1.97(g) the filing of this Information Disclosure Statement shall not be construed to mean that a search has been made or that no other material information as defined in 37 CFR § 1.56 (a) exists.

The attached form, PTO-1449, provides a listing of patents, publications, or other information as required by 37 CFR § 1.98 (a)(1).

A copy of each of the items on PTO-1449 is supplied herewith.

Respectfully submitted,

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In Place of FORM PTO-1449 (Modified)

**LIST OF PATENTS AND PUBLICATIONS FOR
APPLICANT'S INFORMATION DISCLOSURE
STATEMENT**

Serial No. _____
 Applicant: Crawford, et. al.
 Filing Date: _____
 Group: _____
 Atty. Docket No. RSW920030203US1

U. S. PATENT DOCUMENTS

Examiner <u>Initial</u>	Document <u>Number</u>	Date	Name	Class	Subclass	Filing Date if Appropriate
/MAF/ AA	2003/0018511	Jan 23, 2003	Bicknell et al.	705	9	
/MAF/ AB	6,535,775	Mar 18, 2003	Bagepalli et al.	700	109	
/MAF/ AC	2003/0135399	Jul 17, 2003	Ahamparam et al.	705	7	
/MAF/ AD	2002/0165765	Nov 7, 2002	Sommerfeld et al.	705	14	
/MAF/ AE	5,278,751	Jan 11, 1994	Adiano et al.	364	402	
AF						
AG						
AH						
AI						
AJ						
AK						
AL						

FOREIGN PATENT DOCUMENTS

Examiner <u>Initial</u>	Document <u>Number</u>	Date	Country	Class	Subclass	Translation Yes No
AM	11,288427	Oct 19, 1999	Japan	G06F	17/50	No
AN						
AO						
AP						

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner <u>Initial</u>	AQ	Vouk, "Software Reliability Engineering," <u>2000 Annual Reliability and Maintainability Symposium</u> , 2000.
AR		
AS		
AT		

Examiner: /Mark Fleischer/ Date Considered: 03/10/2008

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.